## **IC Transistor Tester**



## **Description:**

The integrated multi-function Circuit Tester is a professional instrument designed for the first-line microelectronic engineering staff, maintenance staff. Different test modes are selectable: 5V mode, 3.3 V mode, auto mode allows testing 74HC Series 74LS series CD4000 series HEF400 series, 4500 series, operational amplifiers, interface class chip, transistor optocoupler automatic identification value regulator recognition, and so on. Built-in 13 kinds of various types of model data chip, the model data transistor more than 420 kinds, covering a majority of 24 feet or less universal common device, can significantly reduce the workload and improve work efficiency.

Directory		Feature
Search	Auto 5.0V 3.3V	The devices search, location model chip inserted in the IC seat can automatically identify the device type, model (three modes selectable, default auto mode) automatic identification without input!
74HC		74H Series logic device test (74LS series the same drive level, with which to judge the level) (manually input models)
74LS		74LS Series logic device test (the 74HC column libraries the same drive level, the threshold to determine the level) (manually input models)
CD40		CD4000 series logic device testing (HEF40 column library, drive level, the same level threshold judgment) (need to manually enter the model)
HEF40		HEF400 series logic device testing (CD40 series library, require manual input drive level threshold to judge the same level)
45/145		45 Series 145 Series logic device testing (manually input models)
OTHER		Interface driver class device testing, such as: ULN2003, ULN2803, 82C251, 75175, 75176, MC3487, 26510, 261531, 26LS32, MAX485, MAX232
AMP		Op Amps, comparators class test, such as: LM324, LM358, LM339, LM393, LM2902, LM2904, LM741, NE555, TL082,TL084
TR		Transistor identification, automatically determine the transistor types and pin order, identifiable NPN, PNP transistor, the N-MOS and P-MOS way thyristor, triac, common anode common cathode rectifier (automatic identification without input)
ZD		The zener regulator testing can test within the range of 0V-50V regulator without entering a precision 0.01V (Automatic identification)
LIGHT		Optocoupler secondary saturated buck test can test the ordinary 4 feet optocoupler secondary saturation voltage (automatic identification without input)
OFF		Shutdown

## **Directory and Features:**

Prompt	Explanation
Batter	Battery voltage
ОК	Tests are normal logic function, threshold, and the driving force
Not found	Not found
Fault	The chip is damaged or type mismatch
Open	Open circuit
Not supported	Does not support
NPN	Triode
PNP	Triode
N-MOS	FET
P-MOS	FET
1-SCR	Way SCR
2-SCR	Triac
2D	Common cathode and common anode rectifier
A, k, b, c, e, g	Specific pin
Out of range	Zener voltage beyond the scope of
ERR1	Self-test failure
ERR2	Self-test failure



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